N-channel TrenchMOS logic level FET

11 September 2012

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in a SOT226 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with VGS(th) rating of greater than 0.5V at 175 °C

1.3 Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Qu	uick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	60	V
I _D	drain current	V _{GS} = 5 V; T _{mb} = 25 °C; <u>Fig. 1</u>	[1]	-	-	120	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	-	293	W
Static charac	cteristics	·					
R _{DSon}	drain-source on-state resistance	V _{GS} = 5 V; I _D = 25 A; T _j = 25 °C; <u>Fig. 11</u>		-	2.91	3.7	mΩ
Dynamic cha	aracteristics	·					
Q _{GD}	gate-drain charge	V _{GS} = 5 V; I _D = 25 A; V _{DS} = 48 V; Fig. 13; Fig. 14		-	32	-	nC

[1] Continuous current is limited by package.





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2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G
mb	D	mounting base; connected to drain	I2PAK (SOT226)	mbb076 S

3. Ordering information

Table 3. Ordering information					
Type number Package					
	Name	Description	Version		
BUK9E3R7-60E	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	60	V
V _{DGR}	drain-gate voltage	R _{GS} = 20 kΩ		-	60	V
V _{GS} g	gate-source voltage	$T_j \le 175 \ ^{\circ}C; Pulsed$	[1][2]	-15	15	V
		T _j ≤ 175 °C; DC		-10	10	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 5 V; <u>Fig. 1</u>	[3]	-	120	Α
		T_{mb} = 100 °C; V_{GS} = 5 V; <u>Fig. 1</u>	[3]	-	120	А
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 4		-	758	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	293	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	in diode					
I _S	source current	T _{mb} = 25 °C	[<u>3]</u>	-	120	А
I _{SM}	peak source current	pulsed; t _p ≤ 10 µs; T _{mb} = 25 °C		-	758	Α

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Symbol	Parameter	Conditions		Min	Мах	Unit
Avalanche ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 120 A; $V_{sup} \le 60$ V; R_{GS} = 50 Ω; V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; unclamped; Fig. 3	[<u>4][5]</u>	-	404	mJ

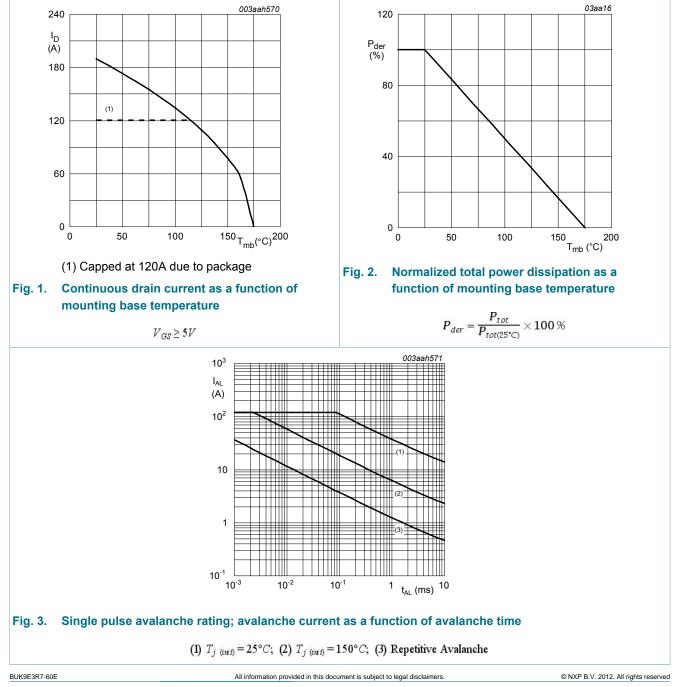
[1] Accumulated pulse duration up to 50 hours delivers zero defect ppm

[2] Significantly longer life times are achieved by lowering $\rm T_{j}$ and or $\rm V_{GS}$

[3] Continuous current is limited by package.

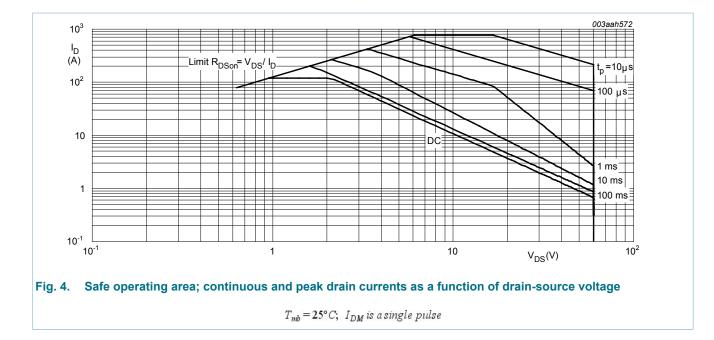
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Refer to application note AN10273 for further information.



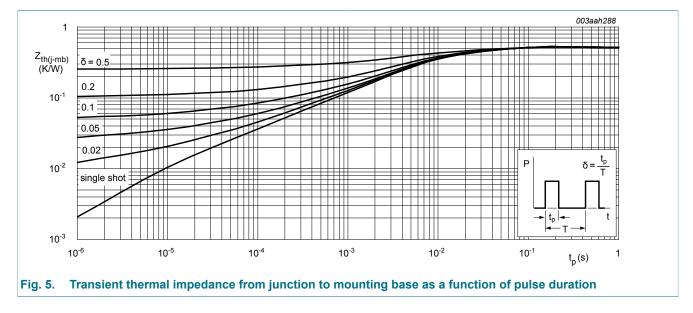
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5. Thermal characteristics

Table 5. The	rmal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. <u>5</u>	-	-	0.51	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in still air	-	65	-	K/W



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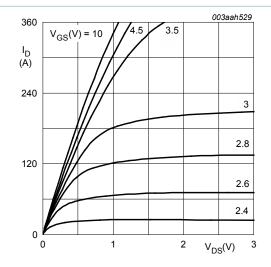
6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics	· · · · ·	I			
V _{(BR)DSS}	drain-source	I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C	60	-	-	V
	breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C	54	-	-	V
V _{GS(th)} gate-sou voltage	-	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; Fig. 9; Fig. 10	1.4	1.7	2.1	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = -55 °C; Fig. 9	-	-	2.45	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ Fig. 9	0.5	-	-	V
I _{DSS}	drain leakage current	V_{DS} = 60 V; V_{GS} = 0 V; T_j = 25 °C	-	0.09	1	μA
		V_{DS} = 60 V; V_{GS} = 0 V; T_j = 175 °C	-	-	500	μA
I _{GSS}	gate leakage current	V_{GS} = 10 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 25 °C	-	2	100	nA
Doon	drain-source on-state	V _{GS} = 5 V; I _D = 25 A; T _j = 25 °C; <u>Fig. 11</u>	-	2.91	3.7	mΩ
	resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; Fig. 11	-	2.67	3.4	mΩ
		V _{GS} = 5 V; I _D = 25 A; T _j = 175 °C; Fig. 12; Fig. 11	-	-	8.1	mΩ
Dynamic cl	naracteristics	· · · · ·	I]
Q _{G(tot)}	total gate charge	I _D = 25 A; V _{DS} = 48 V; V _{GS} = 5 V;	-	95	-	nC
Q _{GS}	gate-source charge	Fig. 13; Fig. 14	-	20	-	nC
Q _{GD}	gate-drain charge		-	32	-	nC
C _{iss}	input capacitance	V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;	-	10115	13490	pF
C _{oss}	output capacitance	T _j = 25 °C; <u>Fig. 15</u>	-	822	990	pF
C _{rss}	reverse transfer capacitance		-	427	585	pF
t _{d(on)}	turn-on delay time	V_{DS} = 45 V; R _L = 1.8 Ω; V _{GS} = 5 V;	-	54	-	ns
t _r	rise time	$R_{G(ext)} = 5 \Omega$	-	100	-	ns
t _{d(off)}	turn-off delay time	-	-	158	-	ns
t _f	fall time		-	109	-	ns
L _D	internal drain inductance	from upper edge of drain mounting base to center of die ; $T_j = 25 \ ^\circ C$	-	2.5	-	nH
		from drain lead 6mm from package to centre of die ; T_i = 25 °C	-	4.5	-	nH

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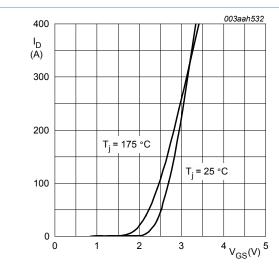
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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
L _S	internal source inductance	from source lead to source bonding pad ; T_j = 25 °C		-	7.5	-	nH
Source-drain o	Source-drain diode						
V _{SD}	source-drain voltage	I_{S} = 25 A; V_{GS} = 0 V; T_{j} = 25 °C; <u>Fig. 16</u>		-	0.78	1.2	V
t _{rr}	reverse recovery time	$I_{\rm S}$ = 20 A; dI_{\rm S}/dt = -100 A/µs; V_{\rm GS} = 0 V;		-	44	-	ns
Q _r	recovered charge	V _{DS} = 25 V		-	67	-	nC



T_j = 25 °C; t_p = 300 μs









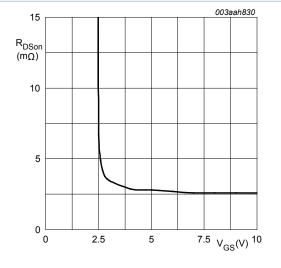
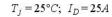


Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values



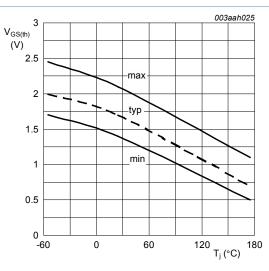
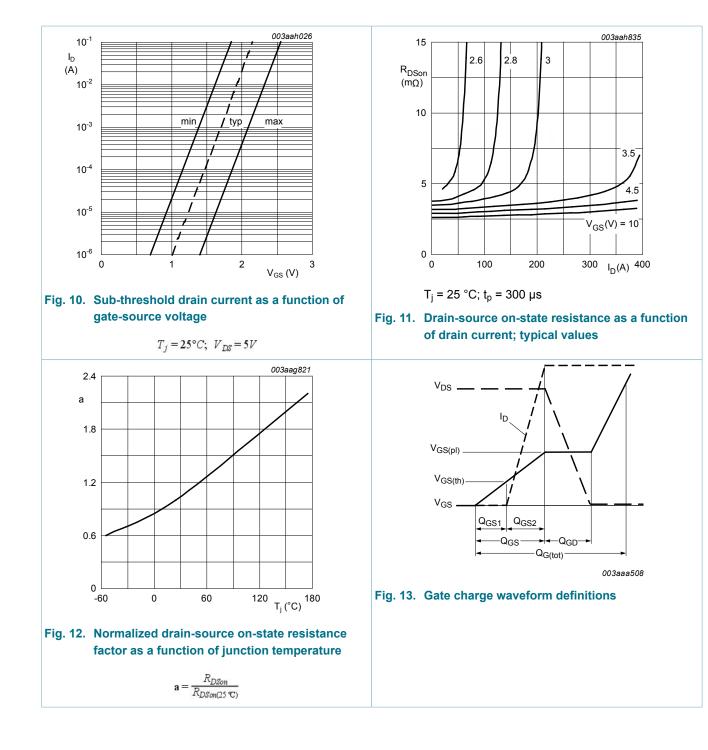


Fig. 9. Gate-source threshold voltage as a function of junction temperature

 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

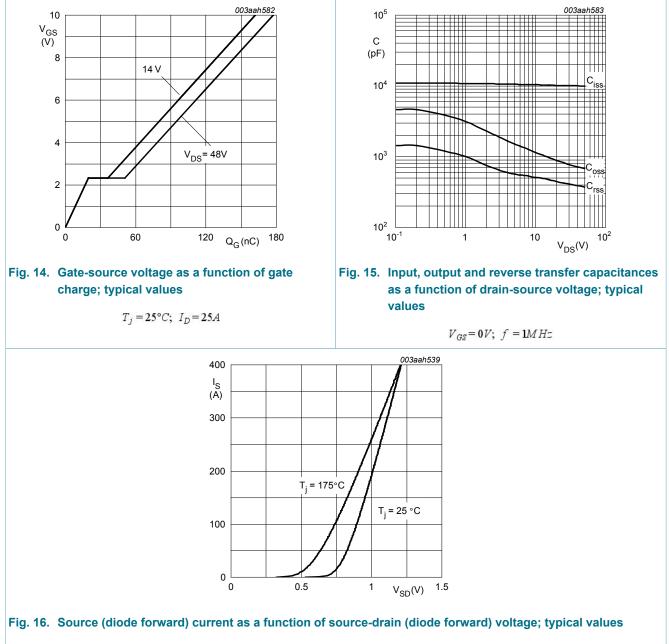
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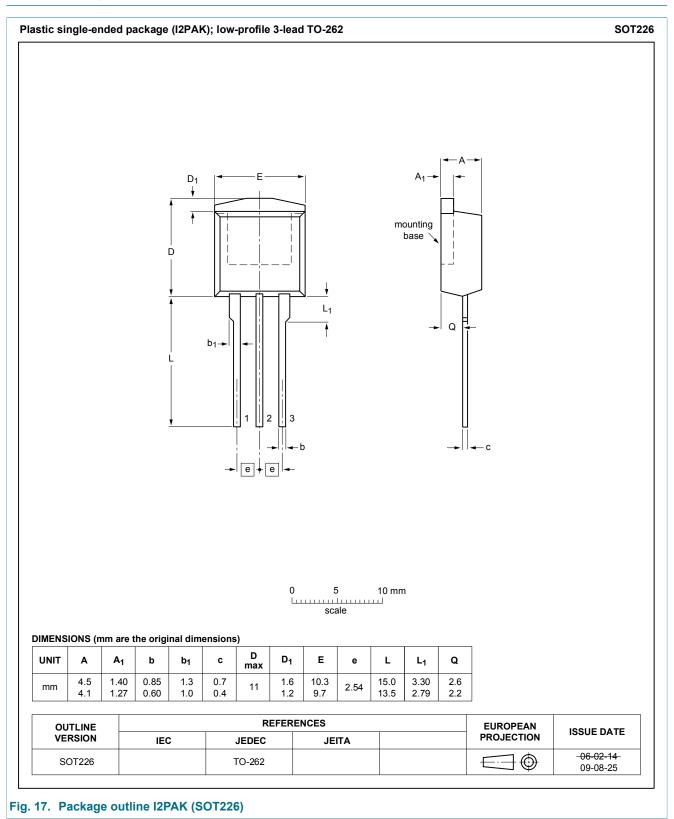
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 $V_{GS} = 0V$

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7. Package outline



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8. Legal information

8.1 Data sheet status

Document status [1][2]	Product status [<u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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